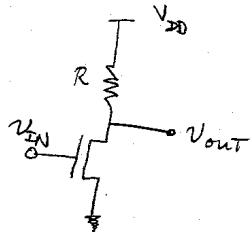


Tutorial Notes - tutorial #5 (10/22/2000 & 10/23/2000)

MOS Inverters

NMOS - Resistor pull-up:



$$V_{out} = V_{DD} - I_D R$$

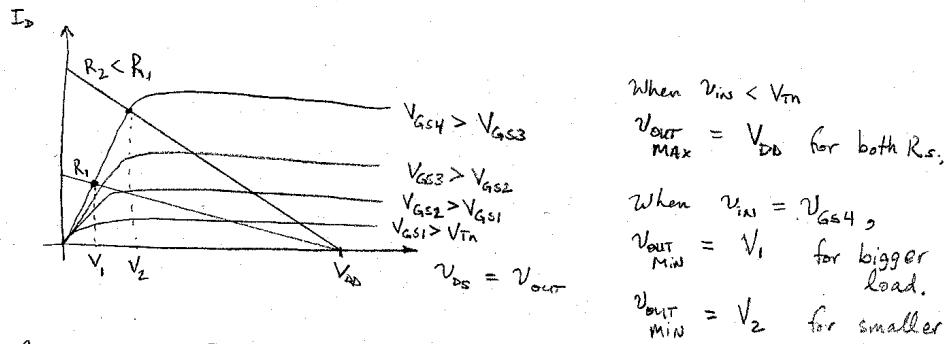
When $I_D = 0$ ($V_{in} < V_{Tn}$)

$$\Rightarrow V_{out} = V_{DD}$$

When $V_{in} > V_{Tn}$, V_{out} is low.

How do we increase the noise margins?

- increase transconductance (increase current).
- increase R .



Conclusion: Bigger load gives greater NM.

$$NM_H = V_{OH} - V_{IH}$$

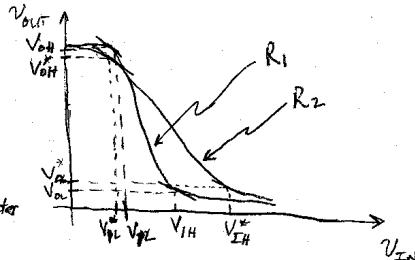
$$NM_L = V_{IL} - V_{OL}$$

$$NM_{H,R_1}$$

$$NM_{H,R_2} = V_{OH}^* - V_{IH}^*$$

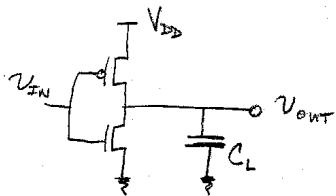
$$NM_{L,R_1} = V_{IL} - V_{OL}$$

$$NM_{L,R_2} = V_{IL}^* - V_{OL}^*$$



- Drawback of higher $R \Rightarrow$ greater RC-time delay.
- Drawback of higher $g_m \Rightarrow$ wider transistor = more capacitance.

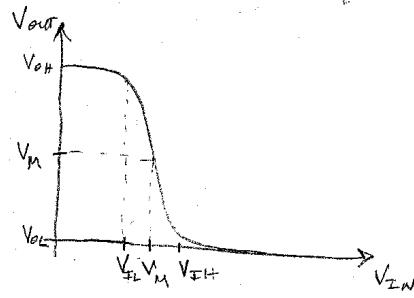
A Better Way \Rightarrow CMOS - inverter:



- When V_{IN} low, NMOS is cut off $\Rightarrow C_L$ charged up to V_{DD} w/ I_D flowing through PFET.

- Power source (V_{DD}) has path to ground only for very short time during switching.
This leads to higher noise margins, faster switching & lower power consumption.

- When V_{IN} high, PFET is cut off $\Rightarrow C_L$ discharged to 0 w/ I_D flowing through NFET.



What is V_M ?

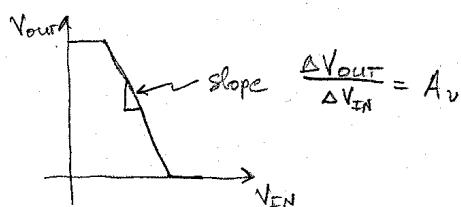
\Rightarrow NFET & PFET both in saturation region when $V_{IN} = V_{OUT} = V_M$

$$I_{DN} = \frac{1}{2} k_n (V_M - V_{TN})^2 \quad \& \quad -I_{DP} = \frac{1}{2} k_p (V_{DD} - V_M + V_{TP})^2$$

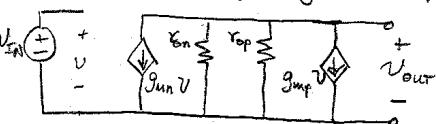
Setting these equal to each other:

$$V_M = \frac{V_{TN} + \sqrt{\frac{k_p}{k_n}} (V_{DD} + V_{TP})}{1 + \sqrt{\frac{k_p}{k_n}}}$$

What is voltage gain?



CMOS Low frequency small signal



$$g_{mn} = k_n (V_M - V_{TN})$$

$$R_{in} = \frac{1}{2n I_{DN}}$$

$$g_{mp} = k_p (V_{DD} - V_M + V_{TP})$$

$$R_{out} = \frac{1}{2p I_{DP}}$$

CMOS - inverter

$$A_v = -(g_{mn} + g_{mp})(r_{on} \parallel r_{op})$$

$$V_{IL} = V_M + \frac{(V_{DD} - V_M)}{A_v} \quad \& \quad V_{IH} = V_M - \frac{V_M}{A_v}$$

$$NM_L = V_{IL} - V_{OL} = V_M + \frac{(V_{DD} - V_M)}{A_v}$$

$$NM_H = V_{OH} - V_{IH} = V_{DD} - V_M + \frac{V_M}{A_v}$$

Transient Analysis:

$t_{PHL} \Rightarrow$ time it takes from input transition from low to high to output transition from high to 50% of $(V_{OH} - V_{OL})$.

$t_{PLH} \Rightarrow$ time it takes from input transition from high to low to output transition from low to 50% of $(V_{OH} - V_{OL})$.

so, $t_{PHL} = \frac{C_L \Delta V}{I_o}$ \leftarrow total charge to be removed from load capacitance.
 $I_o \leftarrow$ rate at which the charge can be removed.

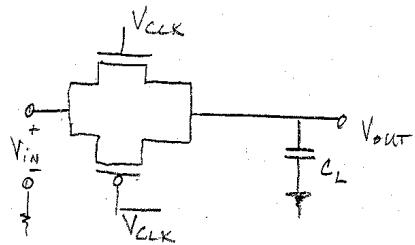
$$t_{PHL} = \frac{C_L \Delta V}{\frac{1}{2} k_n (V_{DD} - V_{Th})^2} \quad \& \quad C_L = C_G + C_{DB} + C_{wire}$$

$$C_{DB} = W_n L_{diffn} (C_{Jn}) + W_p L_{diffp} (C_{Jp}) + (W_n + 2L_{diffn}) C_{JSWn} \\ + (W_p + 2L_{diffp}) C_{JSWP}$$

$$C_G = \sum_{in,} C_{in} \quad \text{where} \quad C_{in} = Cox(W, L)_p + Cox(W, L)_n$$

C_{wire} is parasitic capacitance of wiring/connections.

Pass Gates



Average NFET Current for a low-to-high transition:

$$\overline{I_{DLHn}} = \frac{I_{DLHn}(V_{out} = 0V) + I_{DLHn}(V_{out} = \frac{V_{DD}}{2})}{2}$$

$$= \frac{\frac{k_n}{2}(V_{DD} - V_{T_{on}})^2 + \frac{k_n}{2}(V_{DD} - \frac{V_{DD}}{2} - V_{T_{on}})^2}{2}$$

Average PFET Current for same transition:

$$\overline{I_{DLH_P}} = \frac{k_p}{2}(V_{DD} + V_{T_{off}})^2$$

$$t_{PLH} = \frac{(C_{L_{LH}} \frac{V_{out}}{2})}{(\overline{I_{DLHn}} + \overline{I_{DLH_P}})}$$

$$C_{L_{LH}} = C_G + C_p + \frac{2}{3}(WL)_n C_{ox} + W_p C_{ox}$$

↑ gate caps of load. ↗ parasitics ($= C_{DE} + C_{wire}$). ↗ NFET C_{gs} in saturation.

 ↗ PFET C_{dg} in saturation.

$$t_{PLH} = \frac{(C_{L_{LH}} \frac{V_{out}}{2})}{(\overline{I_{DLHn}} + \overline{I_{DLH_P}})} \quad \& \quad \overline{I_{DHLP}} = \frac{\frac{k_p}{2}(V_{DD} + V_{T_{off}})^2 + \frac{k_p}{2}(V_{DD} - \frac{V_{DD}}{2} + V_{T_{off}})^2}{2}$$

$$\overline{I_{DHLn}} = \frac{k_n}{2}(V_{DD} - V_{T_{on}})^2$$

$$C_{L_{HL}} = C_G + C_p + \frac{2}{3}(WL)_p C_{ox} + W_n C_{ox}$$